

# STGE50NC60WD

### N-channel 50A - 600V - ISOTOP Ultra fast switching PowerMESH™ IGBT

#### **Features**

Туре	V <sub>CES</sub>	V <sub>CE(sat)</sub> (Max) @25°C	l <sub>C</sub> @100°C
STGE50NC60WD	600V	2.5V	50A

- High current capability
- High frequency operation
- Low C<sub>RES</sub>/C<sub>IES</sub> ratio (no cross-conduction susceptibility
- Very soft ultra fast recovery antiparallel diode

### Description

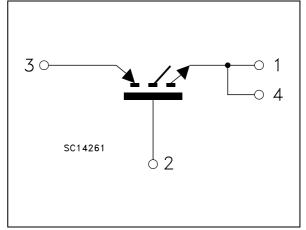
Using the latest high voltage technology based on a patented strip layout, STMicroelectronics has designed an advanced family of IGBTs, the PowerMESH<sup>™</sup> IGBTs, with outstanding performances. The suffix "W" identifies a family optimized for very high frequency applications.

### Applications

- Very high frequency inverters
- HF, SMPS and PFC in both hard switching and resonant topologies
- UPS
- Motor drivers
- Welding

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Figure 1. Internal schematic diagram



Order code	Marking	Package	Packaging
STGE50NC60WD	GE50NC60WD	ISOTOP	Tube

## Contents

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# 1 Electrical ratings

Table 2.	Absolute maximum ratings
	Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>CES</sub>	Collector-emitter voltages <sub>GS</sub> = 0)	600	V
I <sub>C</sub> <sup>(1)</sup>	Collector current (continuous) at $T_{C} = 25^{\circ}C$	100	А
I <sub>C</sub> <sup>(1)</sup>	Collector current (continuous) at T <sub>C</sub> = 100°C	50	А
I <sub>CL</sub> <sup>(2)</sup>	Collector current (pulsed)	250	А
V <sub>GE</sub>	Gate-emitter voltage	± 20	V
١ <sub>F</sub>	Diode RMS forward current at Tc=25°C	30	А
P <sub>TOT</sub>	Total dissipation at $T_{C} = 25^{\circ}C$	260	W
T <sub>stg</sub>	Storage temperature	-55 to 150	°C
Tj	Operating junction temperature	-55 10 150	0

1. Calculated according to the iterative formula:

$$I_{C}(T_{C}) = \frac{T_{JMAX}^{-T}C}{R_{THJ-C} \times V_{CESAT(MAX)}^{-T}(T_{C}, I_{C})}$$

2. Pulse width limited by Tjmax

#### Table 3. Thermal resistance

Symbol	ol Parameter		Тур	Мах	Unit
Rthj-case	Thermal resistance junction-case (IGBT)			0.48	°C/W
Rthj-case	Rthj-case Thermal resistance junction-case (diode)			1.5	°C/W
Rthj-amb	Thermal resistance junction-amb			50	°C/W

## 2 Electrical characteristics

(T<sub>J</sub> = 25 °C unless otherwise specified)

#### Table 4. Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>BR(CES)</sub>	Collector-emitter breakdown voltage	I <sub>C</sub> = 1mA, V <sub>GE</sub> = 0	600			V
V <sub>CE(sat)</sub>	Collector-emitter saturation voltage	V <sub>GE</sub> = 15V, I <sub>C</sub> = 40A V <sub>GE</sub> = 15V, I <sub>C</sub> =40A,Tc=125°C		2.1 1.9	2.6	V V
V <sub>GE(th)</sub>	Gate threshold voltage	$V_{CE} = V_{GE}$ , $I_C = 250 \ \mu A$	3.75		5.75	V
I <sub>CES</sub>	Collector cut-off current (V <sub>GE</sub> = 0)	V <sub>CE</sub> = Max rating,T <sub>C</sub> = 25°C V <sub>CE</sub> = Max rating,T <sub>C</sub> = 125°C			500 5	μA mA
I <sub>GES</sub>	Gate-emitter leakage current (V <sub>CE</sub> = 0)	$V_{GE}$ = ±20V, $V_{CE}$ = 0			±100	nA
9 <sub>fs</sub>	Forward transconductance	$V_{CE} = 15V_{,} I_{C} = 40A$		25		S

#### Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>ies</sub> C <sub>oes</sub> C <sub>res</sub>	Input capacitance Output capacitance Reverse transfer capacitance	V <sub>CE</sub> = 25V, f = 1MHz, V <sub>GE</sub> = 0		4700 410 90		pF pF pF
Q <sub>g</sub> Q <sub>ge</sub> Q <sub>gc</sub>	Total gate charge Gate-emitter charge Gate-collector charge	$V_{CE}$ = 390V, I <sub>C</sub> = 40A, $V_{GE}$ = 15V, <i>Figure 17</i>		195 32 82		nC nC nC



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub> (di/dt) <sub>on</sub>	Turn-on delay time Current rise time Turn-on current slope	$V_{CC} = 390V, I_C = 40A$ $R_G = 3.3\Omega, V_{GE} = 15V,$ <i>Figure 16, Figure 18</i>		52 17 2400		ns ns A/µs
t <sub>d(on)</sub> t <sub>r</sub> (di/dt) <sub>on</sub>	Turn-on delay time Current rise time Turn-on current slope	$V_{CC} = 390V, I_C = 40A$ $R_G = 3.3\Omega, V_{GE} = 15V,$ $Tj = 125^{\circ}C$ <i>Figure 16, Figure 18</i>		50 19 2020		ns ns A/µs
t <sub>r(Voff)</sub> t <sub>d(Voff)</sub> t <sub>f</sub>	Off voltage rise time Turn-off delay time Current fall time	$V_{CC} = 390V, I_C = 40A$ $R_G = 3.3\Omega, V_{GE} = 15V,$ <i>Figure 16, Figure 18</i>		31 240 35		ns ns ns
t <sub>r(Voff)</sub> t <sub>d(Voff)</sub> t <sub>f</sub>	Off voltage rise time Turn-off delay time Current fall time	$V_{CC} = 390V, I_C = 40A$ $R_G = 3.3\Omega, V_{GE} = 15V,$ $Tj = 125^{\circ}C$ <i>Figure 16, Figure 18</i>		59 280 63		ns ns ns

 Table 6.
 Switching on/off (inductive load)

#### Table 7. Switching energy (inductive load)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
E <sub>on</sub> <sup>(1)</sup> E <sub>off</sub> <sup>(2)</sup> E <sub>ts</sub>	Turn-on switching losses Turn-off switching losses Total switching losses	$V_{CC} = 390V, I_C = 40A$ $R_G = 3.3\Omega, V_{GE} = 15V,$ <i>Figure 18</i>		365 560 925	470 790 1260	μJ μJ μJ
E <sub>on</sub> <sup>(1)</sup> E <sub>off</sub> <sup>(2)</sup> E <sub>ts</sub>	Turn-on switching losses Turn-off switching losses Total switching losses	V <sub>CC</sub> = 390V, I <sub>C</sub> = 40A R <sub>G</sub> = 3.3Ω, V <sub>GE</sub> = 15V, Tj = 125°C <i>Figure 18</i>		635 910 1545		μJ μJ μJ

 Eon is the tun-on losses when a typical diode is used in the test circuit in *Figure 18* If the IGBT is offered in a package with a co-pak diode, the co-pack diode is used as external diode. IGBTs & Diode are at the same temperature (25°C and 125°C)

2. Turn-off losses include also the tail of the collector current



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>f</sub>	Forward on-voltage	l <sub>f</sub> = 15A l <sub>f</sub> = 15A, Tj = 125°C l <sub>f</sub> = 40A, Tj = 125°C		1.5 1.2 1.35	2.9	V V V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>rrm</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	l <sub>f</sub> = 40A,V <sub>R</sub> = 50V, Tj = 25°C, di/dt = 100 A/μs <i>Figure 19</i>		55 100 3.6		ns nC A
t <sub>rr</sub> Q <sub>rr</sub> I <sub>rrm</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	I <sub>f</sub> = 40A,V <sub>R</sub> = 50V, Tj =125°C, di/dt = 100A/μs <i>Figure 19</i>		164 525 6.4		ns nC A

 Table 8.
 Collector-emitter diode



### 2.1 Electrical characteristics (curves)

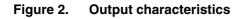


Figure 3. Transfer characteristics

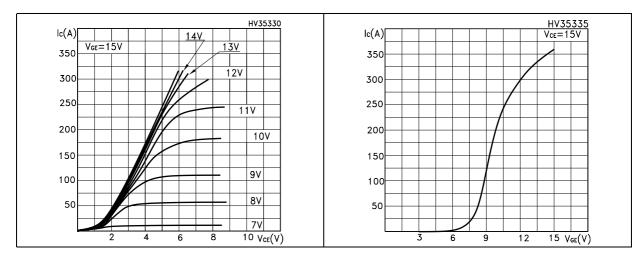




Figure 5.



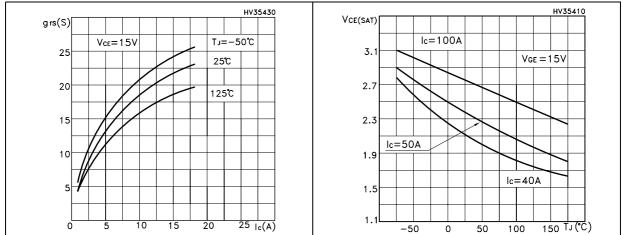
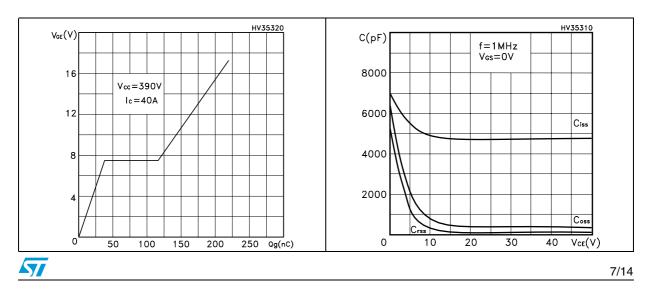


Figure 6. Gate charge vs gate-source voltage Figure 7. Capacitance variations



# Figure 8. Normalized gate threshold voltage Figure 9. vs temperature



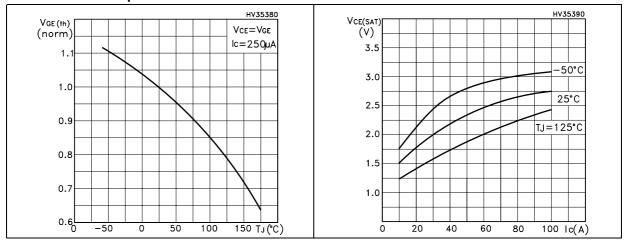


Figure 10. Normalized breakdown voltage vs Figure 11. Switching losses vs temperature temperature

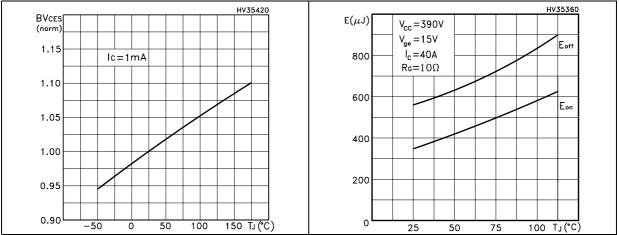


Figure 12. Switching losses vs gate resistance Figure 13. Switching losses vs collector current

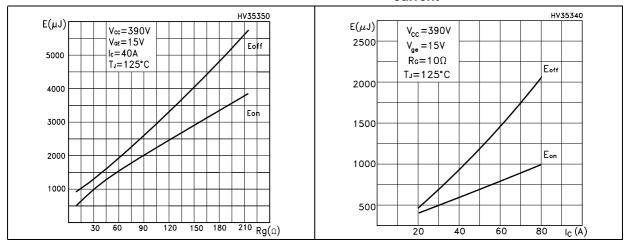


Figure 14. Turn-off SOA

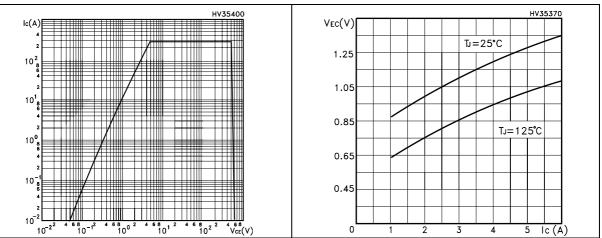


Figure 15. Emitter-collector diode characteristics



## 3 Test circuit

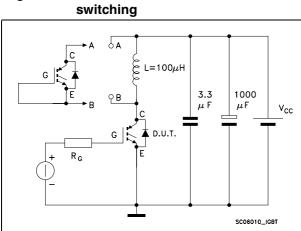


Figure 16. Test circuit for inductive load

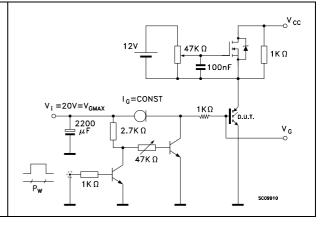
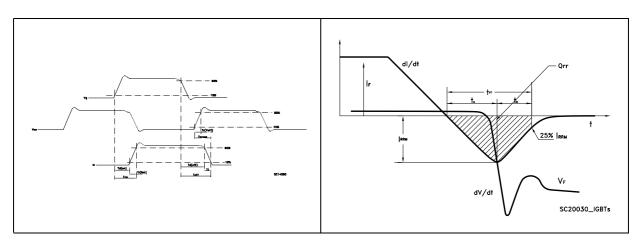
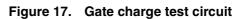


Figure 18. Switching waveform







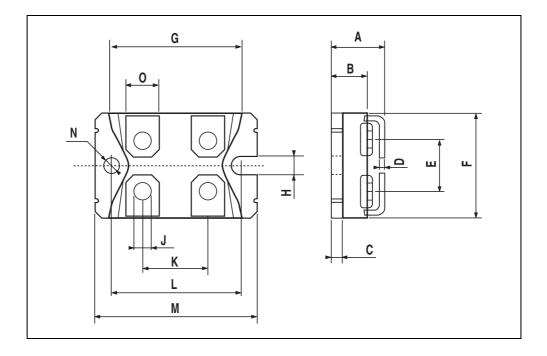
## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: *www.st.com* 



DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	11.8		12.2	0.466		0.480
В	8.9		9.1	0.350		0.358
С	1.95		2.05	0.076		0.080
D	0.75		0.85	0.029		0.033
E	12.6		12.8	0.496		0.503
F	25.15		25.5	0.990		1.003
G	31.5		31.7	1.240		1.248
н	4			0.157		
J	4.1		4.3	0.161		0.169
К	14.9		15.1	0.586		0.594
L	30.1		30.3	1.185		1.193
М	37.8		38.2	1.488		1.503
Ν	4			0.157		
0	7.8		8.2	0.307		0.322

#### **ISOTOP MECHANICAL DATA**





# 5 Revision History

Table 9.	<b>Revision history</b>

Date	Revision	Changes	
07-May-2006	1	First release	
24-Jul-2007	2	New Figure 1: Internal schematic diagram	



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